

# PXI LCR Bundle

Expandable PXI Bundle with LCR Meter

## Use PXI LCR Bundle for

- Combining measurements from different instruments in one system
- CV/IV testing with high channel density and no connection changes at the device under test (DUT)
- MEMS Structure Electrical Test
- Wafer Parametric Test
- Multilayer Ceramic Capacitor (MLCC) Validation & Test



## Popular Features

### 2-in-1

SMU and LCR meter combined in single instrument for an elegant bench solution

### Scalability

Combine with other types of instruments to build tightly integrated mixed signal test systems

### Precision

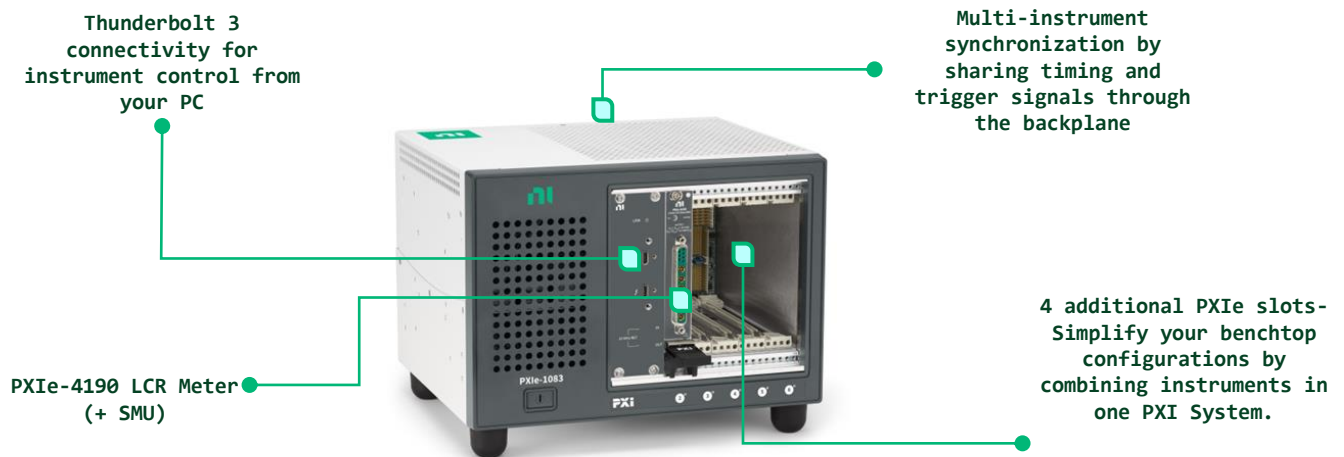
Femtofarad-class capacitance measurements and femtoampere-class current measurements



# Do more in one box with NI PXI

The NI PXI LCR Bundle includes a PXIe-4190 LCR Meter in a 5-slot PXI Express based measurement system that is controlled through your laptop's Thunderbolt™ USB-C port.

Achieve high accuracy, high productivity, and higher speeds with the standard for automated test and automated measurement: NI PXI (PCI eXtensions for Instrumentation).



Make DC and impedance measurements in a seamless fashion with NI's PXIe-4190 - the world's first LCR Meter and SMU in a single instrument. This instrument provides femto-farad (10-15) class capacitance measurements and femto-amp current measurements in a single-slot PXI form factor. The new PXIe-4190 also removes the need for an additional switch to multiplex between the LCR Meter and SMU, allowing for a simplified test experience with higher throughput and lower capital cost.

PXIe-LCR5100 P/N: 867113-01	
<b>What is Included</b>	
<b>Chassis</b>	PXIe-1083
<b>Module</b>	PXIe-4190
<b>Accessories</b>	Thunderbolt cable Power cable, US DSub-to-BNC cable for I/O connectivity
<b>Key Specifications</b>	
<b>Bandwidth</b>	2 Mhz
<b>Voltage Range</b>	± 40 V DC Bias
<b>Max Current</b>	100 mA
<b>Current Ranges</b>	100 mA, 10 mA, 1 mA 100 µA, 10 µA, 1uA, 10nA, 1nA



# Upgrade and do more with your system!

Use the remaining 4 slots to build on top of your system and manage change. Add measurements, more channels, or new analysis routines without having to purchase a whole new instrument. Don't be limited by vendor-defined configurations; explore over 600 different PXI modules ranging from DC to mmWave.



## Oscilloscopes

- Sample at speeds up to 12.5 GS/s
- 6 GHz of analog bandwidth
- Numerous triggering modes
- Up to 24-bit resolution

**Start with PXIe-5160**



## Digital Multimeters

- Voltage measurements up to 1,000 VDC
- Current measurements up to 3 A
- Resistance measurements up to 5 G $\Omega$
- Isolated Digitizer mode - Up to 1.8 MS/s

**Start with PXIe-4080**



## Digital Instruments

- 32-channel module (up to 512 per chassis)
- 100 MHz vector rate, 39 ps displacement
- Digital voltage -2 V to 6 V,
- PPMU force voltage -2 V to 7 V

**Start with PXIe-6570**



## Waveform Generators

- Up to two 16-bit channels per module
- 800 MS/s with 20, 40, and 80 MHz bandwidth
- Up to 34 channels to build parallel
- Max  $\pm 12$  V and min  $\pm 7.75$  mV output ranges

**Start with PXIe-5413**



## Counters/Timer

- Up to eight 32-bit counter/timers
- TTL/CMOS-compatible digital I/O
- Up to 80 MHz measure frequency
- Onboard high-precision oscillators

**Start with PXIe-6612**



## Source Measure Units (SMU)

- Up to 24 channels (408 per chassis)
- Up to 200 V and 3 A (10 A pulse)
- Current sensitivity down to 10 fA
- Max power per channel of 40W (500W pulse)

**Start with PXIe-4139**



## Power Supplies

- Two isolated, 60W channels per module
- Hardware timing and triggering
- Output disconnect relays
- Four-wire remote sense

**Start with PXI-4110**



## Reconfigurable IO (FPGA)

- Variety of on-board FPGA options
- 12-bit to 18-bit analog input resolution
- Up to 16 analog channels and 126 bidirectional channels
- Up to 1 MS/s analog sample rate

**Start with PXIe-7856**



## Switches

- Electromechanical, Reed, solid state, FET
- Up to 150 V or 2 A
- Up to 544 cross points in a single PXI slot
- 1- and 2-wire options

**Start with PXIe-2527**



## Digital Waveform Instrument

- Standard TTL/CMOS interface voltages and programmable voltage levels
- 32 bidirectional digital channels
- Advanced waveform sequencing and streaming features

**Start with PXIe-6548**



## Multifunction IO

- Voltage measurements up to 10 MS/s/ch
- Analog I/O, Digital I/O, and Counters in a single device
- High speed simultaneous sampling up to 14MS/s/ch
- Up to 836 AI single ended channels in 4U of rack space

**Start with PXIe-6363**

Contact your NI product expert to get help solving your test challenges.



# Choose how you like to work with flexible NI Software

## Interactive- skip programming and control your instruments with InstrumentStudio

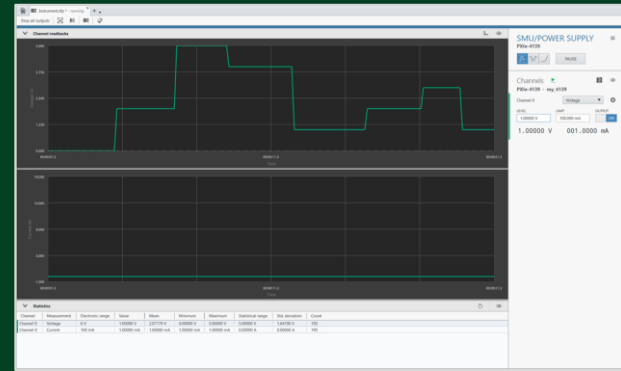
- **Control** all your instruments in a single, intuitive no-code application software.
- **Capture** screenshots, **export** data, and **share** projects with colleagues and between systems.
- **Monitor and debug** automated test systems

## Programming- Build an Automated Test System with LabVIEW

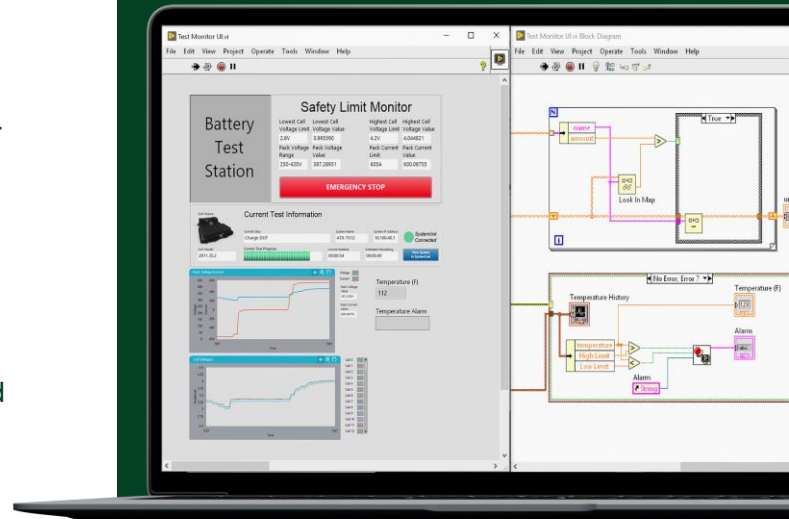
- **Acquire, process and analyze data** from NI hardware, 3<sup>rd</sup> party instruments, and many industry-standard protocols
- **Create interactive UIs** for test monitoring and control.
- **Save data** to .csv, .tdms, or any custom-defined binary file.
- **Integrate code** written in Python, C/C++, .NET, and MathWorks MATLAB® software.

## Why choose? Program or don't based on your task with a Test Workflow Bundle

- **Create** automated test sequences with TestStand
- **Perform** data acquisition and logging with FlexLogger™ software
- **Build** web applications for test with G Web Development Software
- **Interactively analyze** your data with Diadem



With InstrumentStudio, view data from all your instruments unified on high-resolution monitors rather than small, integrated displays.



"The move to a COTS approach using PXI and LabVIEW was critical to this production-test success at Philips. The combination of best-in-class modular hardware along with industry-standard software was pivotal to the millions of dollars and hundreds of hours saved in production test engineering"

-Neil Evans  
Senior Manager, Philips

